

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination UMEZAWA ET AL.
	Examiner Shin-Lin Chen	Art Unit 1632

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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	G	US-			
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	J	US-			
	K	US-			
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	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N	WO 02/44720 A2	06-2002	WIPO	JALINK, Kees	
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**NON-PATENT DOCUMENTS**

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